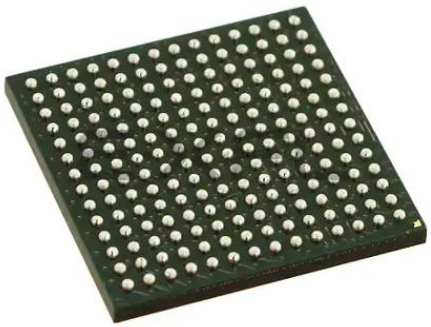

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Details	
Product Status	Not For New Designs
Core Processor	Coldfire V2
Core Size	32-Bit Single-Core
Speed	100MHz
Connectivity	CANbus, EBI/EMI, I²C, SPI, UART/USART
Peripherals	DMA, WDT
Number of I/O	97
Program Memory Size	-
Program Memory Type	ROMless
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	1.4V ~ 1.6V
Data Converters	-
Oscillator Type	External
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	196-LBGA
Supplier Device Package	196-LBGA (15x15)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mcf5232cvm100

Table 2. MCF523x Signal Information and Muxing (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Dir.[1]	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA
ECRS	—	—	—	I	—	—	—	F4	F4
ERXCLK	—	—	—	I	—	—	—	E3	E3
ERXDV	—	—	—	I	—	—	—	E4	E4
ERXD[3:0]	—	—	—	I	—	—	—	D3, D4, C3, C4	D3, D4, C3, C4
ERXER	—	—	—	I	—	—	—	D5	D5
ETXCLK	—	—	—	I	—	—	—	C5	C5
ETXEN	—	—	—	O	—	—	—	D6	D6
ETXER	—	—	—	O	—	—	—	C6	C6
ETXD[3:0]	—	—	—	O	—	—	—	B6, B5, A5, B7	B6, B5, A5, B7
Feature Control									
eTPU/$\overline{\text{EthENB}}$	—	—	—	I	—	—	—	—	M4
I^2C									
I2C_SDA	PFECI2C1	CAN0RX	—	I/O	—	J12	L15	L15	L15
I2C_SCL	PFECI2C0	CAN0TX	—	I/O	—	J11	L14	L14	L14
DMA									
DACK[2:0] and $\overline{\text{DREQ}}$[2:0] do not have a dedicated bond pads. Please refer to the following pins for muxing: $\overline{\text{TS}}$ and DT2OUT for DACK2, TSIZ1and DT1OUT for $\overline{\text{DACK1}}$, TSIZ0 and DT0OUT for $\overline{\text{DACK0}}$, $\overline{\text{IRQ2}}$ and DT2IN for $\overline{\text{DREQ2}}$, $\overline{\text{TEA}}$ and DT1IN for $\overline{\text{DREQ1}}$, and $\overline{\text{TIP}}$ and DT0IN for $\overline{\text{DREQ0}}$.					—	—	—	—	—
QSPI									
QSPI_CS1	PQSPI4	SD_CKE	—	O	139	B7	B10	B10	B10
QSPI_CS0	PQSPI3	—	—	O	147	A6	D9	D9	D9
QSPI_CLK	PQSPI2	I2C_SCL	—	O	148	C5	B8	B8	B8
QSPI_DIN	PQSPI1	I2C_SDA	—	I	149	B5	C8	C8	C8
QSPI_DOUT	PQSPI0	—	—	O	150	A5	D8	D8	D8
UARTs									
U2TXD	PUARTH1	CAN1TX	—	O	—	A8	D11	D11	D11
U2RXD	PUARTH0	CAN1RX	—	I	—	A7	D10	D10	D10
$\overline{\text{U1CTS}}$	PUARTL7	$\overline{\text{U2CTS}}$	—	I	—	B8	C11	C11	C11
$\overline{\text{U1RTS}}$	PUARTL6	$\overline{\text{U2RTS}}$	—	O	—	C8	B11	B11	B11
U1TXD	PUARTL5	CAN0TX	—	O	135	D9	A12	A12	A12

Table 2. MCF523x Signal Information and Muxing (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Dir.[1]	MCF5232 160 QFP	MCF5232 196 MAPBGA	MCF5233 256 MAPBGA	MCF5234 256 MAPBGA	MCF5235 256 MAPBGA
U1RXD	PUARTL4	CAN0RX	—	I	136	D8	A11	A11	A11
$\overline{\text{U0CTS}}$	PUARTL3	—	—	I	—	F3	G1	G1	G1
$\overline{\text{U0RTS}}$	PUARTL2	—	—	O	—	G3	H3	H3	H3
U0TXD	PUARTL1	—	—	O	14	F1	H2	H2	H2
U0RXD	PUARTL0	—	—	I	13	F2	G2	G2	G2
DMA Timers									
DT3IN	PTIMER7	$\overline{\text{U2CTS}}$	QSPI_CS2	I	—	H14	J15	J15	J15
DT3OUT	PTIMER6	$\overline{\text{U2RTS}}$	QSPI_CS3	O	—	G14	J16	J16	J16
DT2IN	PTIMER5	$\overline{\text{DREQ2}}$	DT2OUT	I	—	M9	P10	P10	P10
DT2OUT	PTIMER4	DACK2	—	O	—	L9	R10	R10	R10
DT1IN	PTIMER3	$\overline{\text{DREQ1}}$	DT1OUT	I	—	L6	P7	P7	P7
DT1OUT	PTIMER2	DACK1	—	O	—	M6	R7	R7	R7
DT0IN	PTIMER1	$\overline{\text{DREQ0}}$	—	I	—	E4	G4	G4	G4
DT0OUT	PTIMER0	DACK0	—	O	—	F4	G3	G3	G3
BDM/JTAG[2]									
DSCLK	—	TRST	—	I	70	N9	N11	N11	N11
PSTCLK	—	TCLK	—	O	68	P9	T10	T10	T10
$\overline{\text{BKPT}}$	—	TMS	—	I	71	P10	P11	P11	P11
DSI	—	TDI	—	I	73	M10	T11	T11	T11
DSO	—	TDO	—	O	72	N10	R11	R11	R11
JTAG_EN	—	—	—	I	78	K9	N13	N13	N13
DDATA[3:0]	—	—	—	O	—	M12, N12, P12, L11	N14, P14, T13, R13	N14, P14, T13, R13	N14, P14, T13, R13
PST[3:0]	—	—	—	O	77:74	M11, N11, P11, L10	T12, R12, P12, N12	T12, R12, P12, N12	T12, R12, P12, N12

5.2.1.2 Power Down Sequence

If V_{DD} is powered down first, then sense circuits in the I/O pads cause all output drivers to be in a high impedance state. There is no limit on how long after V_{DD} powers down before OV_{DD}/V_{DDPLL} must power down. V_{DD} should not lag OV_{DD} or V_{DDPLL} going low by more than 0.4 V during power down or there will be undesired high current in the ESD protection diodes. There are no requirements for the fall times of the power supplies.

The recommended power down sequence is as follows:

1. Drop V_{DD} to 0 V.
2. Drop OV_{DD}/V_{DDPLL} supplies.

5.3 Decoupling

- Place the decoupling caps as close to the pins as possible, but they can be outside the footprint of the package.
- 0.1 μF and 0.01 μF at each supply input

5.4 Buffering

- Use bus buffers on all data/address lines for all off-board accesses and for all on-board accesses when excessive loading is expected. See Section 7, “Electrical Characteristics.”

5.5 Pull-up Recommendations

- Use external pull-up resistors on unused inputs. See pin table.

5.6 Clocking Recommendations

- Use a multi-layer board with a separate ground plane.
- Place the crystal and all other associated components as close to the EXTAL and XTAL (oscillator pins) as possible.
- Do not run a high frequency trace around crystal circuit.
- Ensure that the ground for the bypass capacitors is connected to a solid ground trace.
- Tie the ground trace to the ground pin nearest EXTAL and XTAL. This prevents large loop currents in the vicinity of the crystal.
- Tie the ground pin to the most solid ground in the system.
- Do not connect the trace that connects the oscillator and the ground plane to any other circuit element. This tends to make the oscillator unstable.
- Tie XTAL to ground when an external oscillator is clocking the device.

5.7.3 FlexCAN

The FlexCAN module interface to the CAN bus is composed of 2 pins: CANTX and CANRX, which are the serial transmitted data and the serial received data. The use of an external CAN transceiver to interface to the CAN bus is generally required. The transceiver is capable of driving the large current needed for the CAN bus and has current protection, against a defective CAN bus or defective stations.

5.7.4 BDM

Use the BDM interface as shown in the M523*x*EVB evaluation board user's manual. The schematics for this board are accessible at the Freescale website at: http://www.freescale.com/coldfire.

6 Mechanicals/Pinouts and Part Numbers

This section contains drawings showing the pinout and the packaging and mechanical characteristics of the MCF523*x* devices. See Table 2 for a list the signal names and pin locations for each device.

6.1 Pinout—196 MAPBGA

The following figure shows a pinout of the MCF5232CVMxxx package.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	
A	VSS	TPUCH6	TPUCH3	TPUCH2	QSPI_DOUT	QSPI_CS0	U2RXD	U2TXD	$\overline{CS3}$	$\overline{CS6}$	$\overline{CS4}$	A20	A17	VSS	A
B	TPUCH8	TPUCH7	TPUCH4	TPUCH0	QSPI_DIN	$\overline{BS3}$	QSPI_CS1	$\overline{U1CTS}$	$\overline{CS7}$	$\overline{CS1}$	A23	A19	A16	A15	B
C	TPUCH10	TPUCH9	TPUCH5	TPUCH1	QSPI_CLK	$\overline{BS2}$	$\overline{BS0}$	$\overline{U1RTS}$	$\overline{CS2}$	$\overline{CS5}$	A22	A18	A14	A13	C
D	TPUCH13	TPUCH12	TPUCH11	NC	NC	VDD	$\overline{BS1}$	U1RXD/CAN0RX	U1TXD/CAN0TX	$\overline{CS0}$	A21	A12	A11	A10	D
E	TPUCH14	TPUCH15	TCRCLK	DT0IN	OVDD	VSS	OVDD	SD_CKE	VSS	OVDD	A9	A8	A7	A6	E
F	U0TXD	U0RXD	$\overline{U0CTS}$	DT0OUT	TEST	VSS	OVDD	VSS	OVDD	VSS	VDD	A5	A4	A3	F
G	D31	D30	$\overline{U0RTS}$	VDD	CLKMOD1	OVDD	VSS	OVDD	VSS	LTPU ODIS	A2	A1	A0	DT3OUT	G
H	D29	D28	D27	D26	CLKMOD0	VSS	OVDD	OVDD	OVDD	UTPU ODIS	$\overline{TA}$	$\overline{TIP}$	$\overline{TS}$	DT3IN	H
J	D25	D24	D23	D22	VSS	OVDD	VSS	OVDD	VSS	OVDD	I2C_SCL	I2C_SDA	R/$\overline{W}$	$\overline{TEA}$	J
K	D21	D20	D19	D18	OVDD	OVDD	VSS	OVDD	JTAG_EN	$\overline{RCON}$	$\overline{SD\_SRAS}$	$\overline{SD\_SCAS}$	$\overline{SD\_WE}$	CLKOUT	K
L	D17	D16	D10	VDD	D3	DT1IN	$\overline{IRQ5}$	$\overline{IRQ1}$	DT2OUT	PST0	DDATA0	$\overline{SD\_CS1}$	$\overline{SD\_CS0}$	VSSPLL	L
M	D15	D13	D9	D6	D2	DT1OUT	$\overline{IRQ6}$	$\overline{IRQ2}$	DT2IN	TDI/DSI	PST3	DDATA3	VDDPLL	EXTAL	M
N	D14	D12	D8	D5	D1	$\overline{OE}$	$\overline{IRQ7}$	$\overline{IRQ3}$	$\overline{TRST}$/DSCLK	TDO/DSO	PST2	DDATA2	$\overline{RESET}$	XTAL	N
P	VSS	D11	D7	D4	D0	TSIZ1	TSIZ0	$\overline{IRQ4}$	TCLK/PSTCLK	$\overline{TMS}$/$\overline{BKPT}$	PST1	DDATA1	$\overline{RSTOUT}$	VSS	P
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	

Figure 2. MCF5232CVMxxx Pinout (196 MAPBGA)

6.2.1 Pinout—256 MAPBGA

Figure 4 through Figure 6 show pinouts of the MCF5233CVMxxx, MCF5234CVMxxx, and MCF5235CVMxxx packages.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
A	VSS	TPUCH6	TPUCH4	TPUCH2	TPUCH17	TPUCH1	TPUCH0	VDD	BS1	BS0	U1RXD/ CAN0RX	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	A
B	TPUCH8	TPUCH7	TPUCH5	TPUCH3	TPUCH18	TPUCH19	TPUCH16	QSPI_ CLK	BS2	QSPI_ CS1	U1RTS	CS3	CS1	A23	A20	A19	B
C	TPUCH10	TPUCH9	TPUCH25	TPUCH24	TPUCH22	TPUCH20	I2C_SDA/ U2RXD	QSPI_ DIN	BS3	SD_CKE	U1CTS	CS7	CS5	A22	A18	A17	C
D	TPUCH12	TPUCH11	TPUCH27	TPUCH26	TPUCH23	TPUCH21	I2C_SCL/ U2TXD	QSPI_ DOUT	QSPI_ CS0	U2RXD/ CAN1RX	U2TXD/ CAN1TX	CS2	CS0	A14	A15	A16	D
E	TPUCH14	TPUCH13	TPUCH29	TPUCH28	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	A10	A11	A12	A13	E
F	TCRCLK	TPUCH15	TPUCH31	TPUCH30	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	A7	A8	A9	VSS	F
G	U0CTS	U0RXD	DT0OUT	DT0IN	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A4	A5	A6	VDD	G
H	VDD	U0TXD	U0RTS	NC	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A0	A1	A2	A3	H
J	VSS	CLK MOD0	CLK MOD1	TEST	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
K	D28	D29	D30	D31	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	TEA	TA	TIP	TS	K
L	D24	D25	D26	D27	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	SD_WE	I2C_SCL/ CAN0TX	I2C_SDA/ CAN0RX	R/W	L
M	D21	D22	D23	NC	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	SD_ CS0	SD_ SRAS	SD_ SCAS	CLKOUT	M
N	D19	D20	D13	D9	NC	D3	D0	TSIZ1	IRQ5	IRQ1	TRST/ DSCLK	PST0	JTAG_ EN	DDATA3	SD_CS1	VSS	N
P	D17	D18	D12	D8	D5	D2	DT1IN	TSIZ0	IRQ4	DT2IN	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	P
R	D16	D15	D11	D7	D4	D1	DT1OUT	IRQ7	IRQ3	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	R
T	VSS	D14	D10	D6	VDD	VSS	OE	IRQ6	IRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RSTOUT	RESET	VSS	T
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

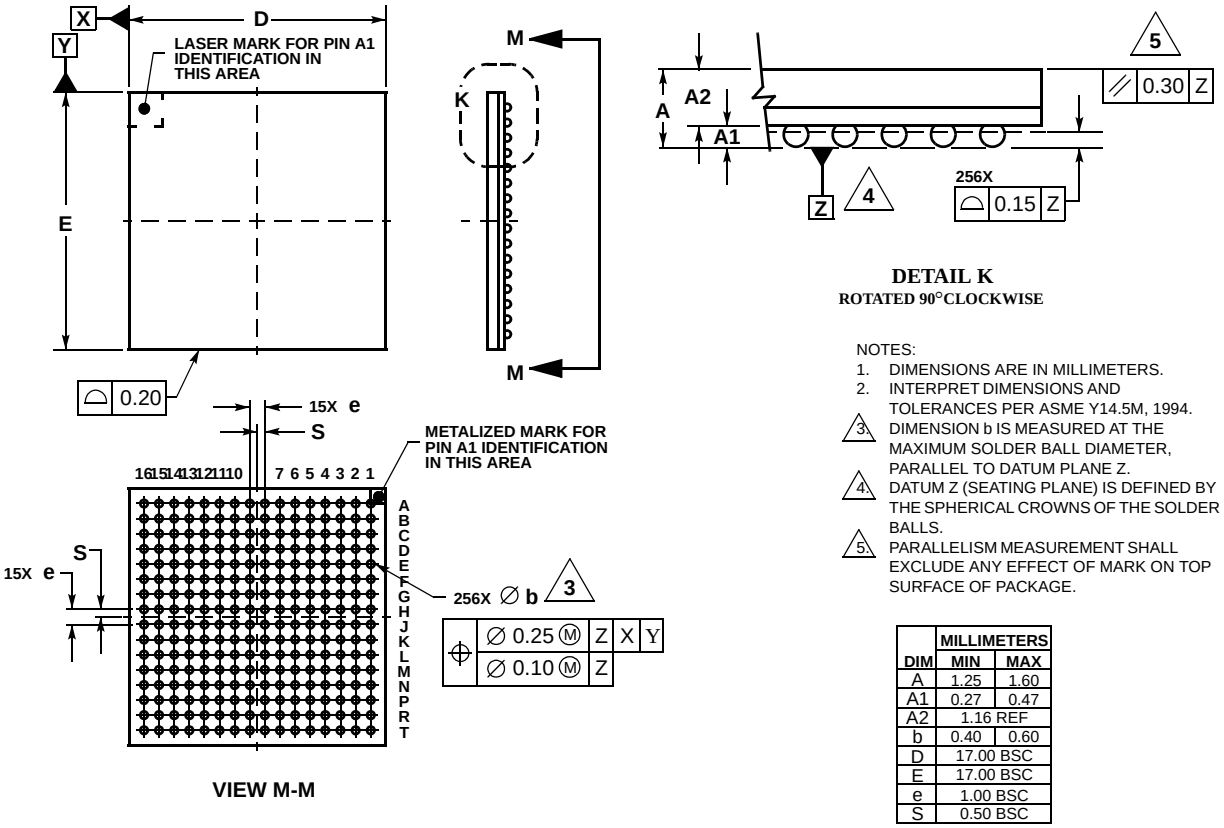
Figure 4. MCF5233CVMxxx Pinout (256 MAPBGA)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
A	VSS	TPUCH6	TPUCH4	TPUCH2	ETXD1	TPUCH1	TPUCH0	VDD	$\overline{BS1}$	$\overline{BS0}$	U1RXD/ CAN0RX	U1TXD/ CAN0TX	$\overline{CS6}$	$\overline{CS4}$	A21	VSS	A
B	TPUCH8	TPUCH7	TPUCH5	TPUCH3	ETXD2	ETXD3	ETXD0	QSPI_ CLK	$\overline{BS2}$	QSPI_ CS1	$\overline{U1RTS}$	$\overline{CS3}$	$\overline{CS1}$	A23	A20	A19	B
C	TPUCH10	TPUCH9	ERXD1	ERXD0	ETXCLK	ETXER	EMDIO	QSPI_ DIN	$\overline{BS3}$	SD_CKE	$\overline{U1CTS}$	$\overline{CS7}$	$\overline{CS5}$	A22	A18	A17	C
D	TPUCH12	TPUCH11	ERXD3	ERXD2	ERXER	ETXEN	EMDC	QSPI_ DOUT	QSPI_ CS0	U2RXD	U2TXD	$\overline{CS2}$	$\overline{CS0}$	A14	A15	A16	D
E	TPUCH14	TPUCH13	ERXCLK	ERXDV	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	A10	A11	A12	A13	E
F	TCRCLK	TPUCH15	ECOL	ECRS	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	A7	A8	A9	VSS	F
G	$\overline{U0CTS}$	U0RXD	DT0OUT	DT0IN	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A4	A5	A6	VDD	G
H	VDD	U0TXD	U0RTS	NC	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	A0	A1	A2	A3	H
J	VSS	CLK MOD0	CLK MOD1	TEST	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
K	D28	D29	D30	D31	OVDD	OVDD	VSS	VSS	VSS	VSS	OVDD	OVDD	$\overline{TEA}$	$\overline{TA}$	$\overline{TIP}$	$\overline{TS}$	K
L	D24	D25	D26	D27	OVDD	VSS	OVDD	OVDD	OVDD	OVDD	VSS	OVDD	$\overline{SD\_WE}$	I2C_SCL/ CAN0TX	I2C_SDA/ CAN0RX	R/$\overline{W}$	L
M	D21	D22	D23	NC	VSS	OVDD	OVDD	OVDD	OVDD	OVDD	OVDD	VSS	$\overline{SD\_CS0}$	$\overline{SD\_ SRAS}$	$\overline{SD\_ SCAS}$	CLKOUT	M
N	D19	D20	D13	D9	NC	D3	D0	TSIZ1	$\overline{IRQ5}$	$\overline{IRQ1}$	$\overline{TRST}$/ DSCLK	PST0	JTAG_ EN	DDATA3	$\overline{SD\_CS1}$	VSS	N
P	D17	D18	D12	D8	D5	D2	DT1IN	TSIZ0	$\overline{IRQ4}$	DT2IN	TMS/ $\overline{BKPT}$	PST1	$\overline{RCON}$	DDATA2	VDDPLL	EXTAL	P
R	D16	D15	D11	D7	D4	D1	DT1OUT	$\overline{IRQ7}$	$\overline{IRQ3}$	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	R
T	VSS	D14	D10	D6	VDD	VSS	$\overline{OE}$	$\overline{IRQ6}$	$\overline{IRQ2}$	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	$\overline{RST\ OUT}$	$\overline{RESET}$	VSS	T
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

Figure 5. MCF5234CVMxxx Pinout (256 MAPBGA)

6.2.2 Package Dimensions—256 MAPBGA

Figure 7 shows MCF5235CVMxxx, MCF5234CVMxxx, and MCF5233CVMxx package dimensions.



NOTES:
1. DIMENSIONS ARE IN MILLIMETERS.
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
3. DIMENSION b IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER, PARALLEL TO DATUM PLANE Z.
4. DATUM Z (SEATING PLANE) IS DEFINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
5. PARALLELISM MEASUREMENT SHALL EXCLUDE ANY EFFECT OF MARK ON TOP SURFACE OF PACKAGE.

	MILLIMETERS	
DIM	MIN	MAX
A	1.25	1.60
A1	0.27	0.47
A2	1.16 REF	
b	0.40	0.60
D	17.00 BSC	
E	17.00 BSC	
e	1.00 BSC	
S	0.50 BSC	

Figure 7. 256 MAPBGA Package Outline

6.3 Pinout—160 QFP

Figure 8 shows a pinout of the MCF5232CABxxx package.

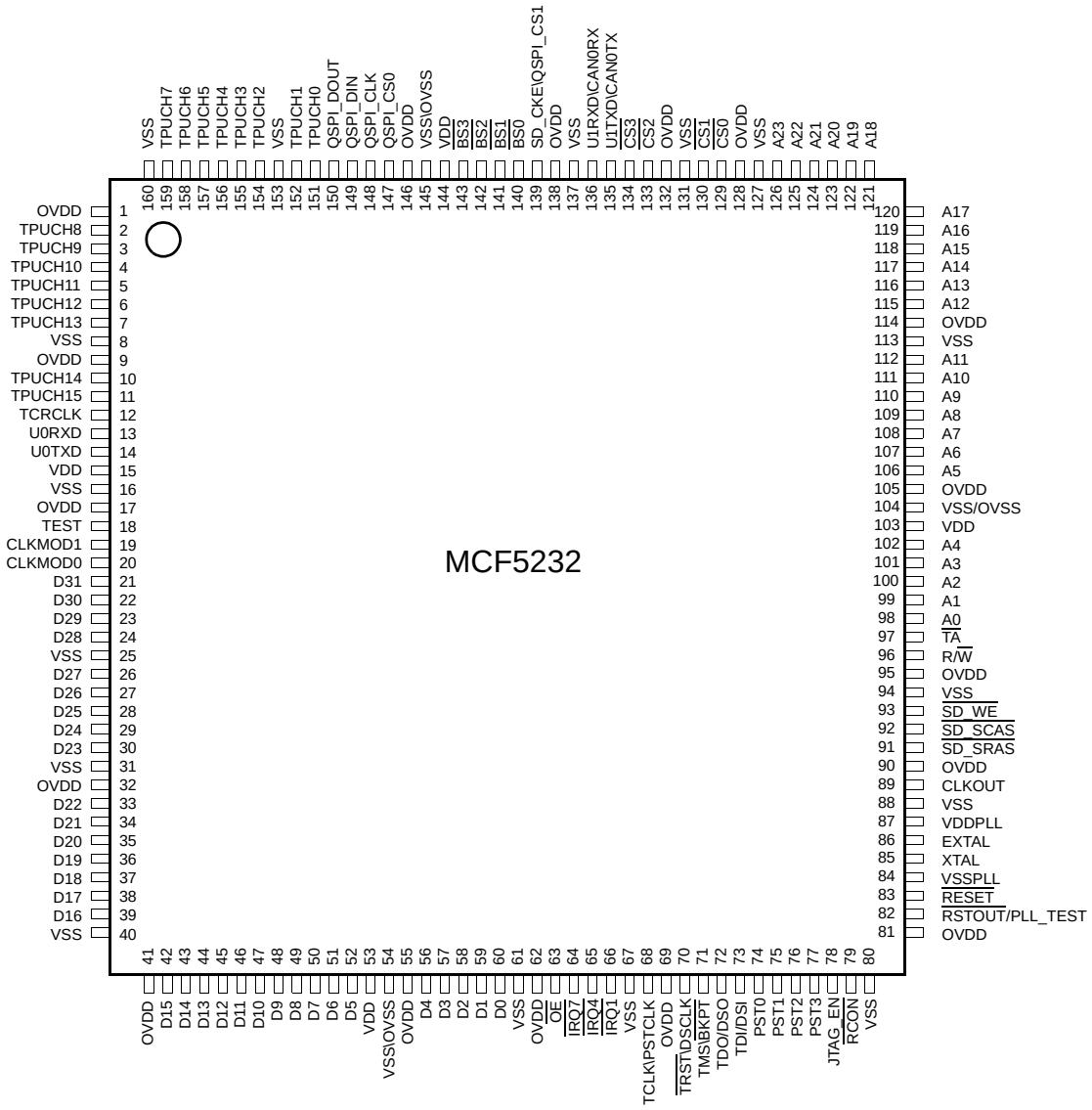
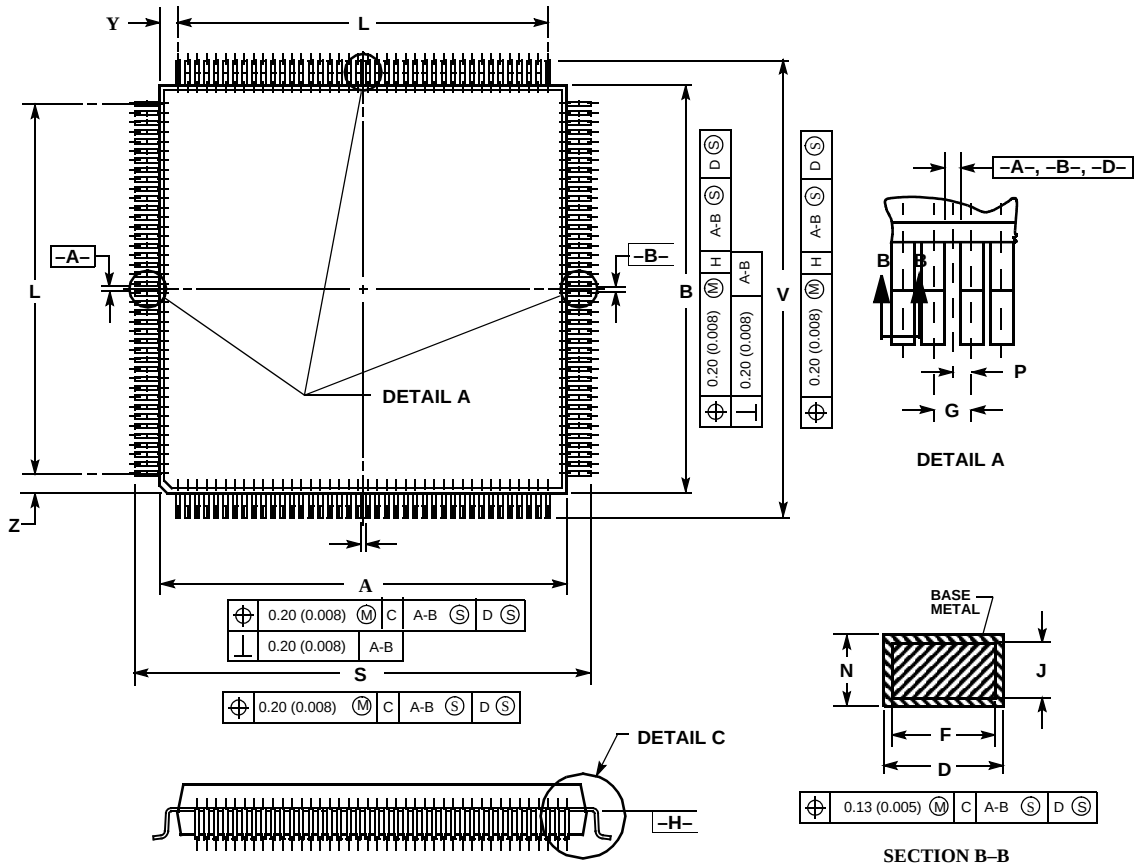
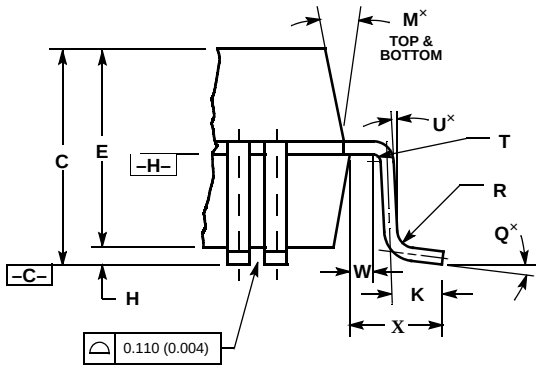


Figure 8. MCF5232CABxxx Pinout (160 QFP)

6.4 Package Dimensions—160 QFP

Figure 9 shows MCF5232CAB80 package dimensions.





DETAIL C

NOTES

1. DIMENSIONING AND TOLERINCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER
3. DATUM PLAN -H- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
4. DATUMS -A-, -B-, AND -D- TO BE DETERMINED AT DATUM PLANE -H-.
5. DIMENSIONS S AND V TO BE DETERMINED AT SEATING PLANE -C-.
6. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 (0.010) PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
7. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	27.90	28.10	1.098	1.106
B	27.90	28.10	1.098	1.106
C	3.35	3.85	0.132	1.106
D	0.22	0.38	0.009	0.015
E	3.20	3.50	0.126	0.138
F	0.22	0.33	0.009	0.013
G	0.65 BSC		0.026 REF	
H	0.25	0.35	0.010	0.014
J	0.11	0.23	0.004	0.009
K	0.70	0.90	0.028	0.035
L	25.35 BSC		0.998 REF	
M	5°	16°	5°	16°
N	0.11	0.19	0.004	0.007
P	0.325 BSC		0.013 REF	
Q	0°	7°	0°	7°
R	0.13	0.30	0.005	0.012
S	31.00	31.40	1.220	1.236
T	0.13	—	0.005	—
U	0°	—	0°	—
V	31.00	31.40	1.220	1.236
W	0.4	—	0.016	—
X	1.60 REF		0.063 REF	
Y	1.33 REF		0.052 REF	
Z	1.33 REF		0.052 REF	

Case 864A-03

Figure 9. 160 QFP Package Dimensions

1 Functional operating conditions are given in DC Electrical Specifications. Absolute Maximum Ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Continued operation at these levels may affect device reliability or cause permanent damage to the device.

2 This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (e.g., either V_{SS} or OV_{DD}).

3 Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.

4 All functional non-supply pins are internally clamped to V_{SS} and OV_{DD}.

5 Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > OV_{DD}$) is greater than I_{DD}, the injection current may flow out of OV_{DD} and could result in external power supply going out of regulation. Insure external OV_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power (ex; no clock).Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions.

7.2 Thermal Characteristics

The below table lists thermal resistance values.

Table 8. Thermal Characteristics

Characteristic		Symbol	256 MAPBGA	196 MAPBGA	160 QFP	Unit
Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JMA}	26[1,2]	32[1,2]	40[1,2]	°C/W
Junction to ambient (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	23[1,2]	29[1,2]	36[1,2]	°C/W
Junction to board		θ_{JB}	15[3]	20[3]	25[3]	°C/W
Junction to case		θ_{JC}	10[4]	10[4]	10[4]	°C/W
Junction to top of package		Ψ_{jt}	2[1,5]	2[1,5]	2[1,5]	°C/W
Maximum operating junction temperature		T_j	102	104	105[6]	°C

1 θ_{JMA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Freescale recommends the use of θ_{JmA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

2 Per JEDEC JESD51-6 with the board horizontal.

3 Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

4 Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).

5 Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.

6 At 100MHz.

7 This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).

8 Assuming a reference is available at power up, lock time is measured from the time V_{DD} and V_{DDSYN} are valid to $\overline{\text{RSTOUT}}$ negating. If the crystal oscillator is being used as the reference for the PLL, then the crystal start up time must be added to the PLL lock time to determine the total start-up time.

9 $t_{lpll} = (64 * 4 * 5 + 5 \times \tau) \times T_{ref}$, where $T_{ref} = 1/F_{ref\_crystal} = 1/F_{ref\_ext} = 1/F_{ref\_1:1}$, and $\tau = 1.57x10^{-6} \times 2(MFD + 2)$.

10 PLL is operating in 1:1 PLL mode.

11 Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum $f_{sys/2}$. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDSYN} and V_{SSSYN} and variation in crystal oscillator frequency increase the Cjitter percentage for a given interval.

12 Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of Cjitter+Cmod.

13 Modulation percentage applies over an interval of 10μs, or equivalently the modulation rate is 100KHz.

14 Modulation rate selected must not result in $f_{sys/2}$ value greater than the $f_{sys/2}$ maximum specified value. Modulation range determined by hardware design.

15 $f_{sys/2} = f_{ico} / (2 * 2^{RFD})$

7.5 External Interface Timing Characteristics

Table 11 lists processor bus input timings.

NOTE

All processor bus timings are synchronous; that is, input setup/hold and output delay with respect to the rising edge of a reference clock. The reference clock is the CLKOUT output.

All other timing relationships can be derived from these values.

Table 11. Processor Bus Input Timing Specifications

Name	Characteristic[1]	Symbol	Min	Max	Unit
freq	System bus frequency	$f_{sys/2}$	50	75	MHz
B0	CLKOUT period	t_{cyc}	—	1/75	ns
Control Inputs					
B1a	Control input valid to CLKOUT high[2]	t_{CVCH}	9	—	ns
B1b	$\overline{\text{BKPT}}$ valid to CLKOUT high[3]	t_{BKVCH}	9	—	ns
B2a	CLKOUT high to control inputs invalid[2]	t_{CHCII}	0	—	ns
B2b	CLKOUT high to asynchronous control input $\overline{\text{BKPT}}$ invalid[3]	t_{BKNCH}	0	—	ns
Data Inputs					
B4	Data input (D[31:0]) valid to CLKOUT high	t_{DIVCH}	4	—	ns
B5	CLKOUT high to data input (D[31:0]) invalid	t_{CHDII}	0	—	ns

1 Timing specifications are tested using full drive strength pad configurations in a 50ohm transmission line environment..

2 $\overline{\text{TEA}}$ and $\overline{\text{TA}}$ pins are being referred to as control inputs.

3 Refer to figure A-19.

Timings listed in Table 11 are shown in Figure 10.

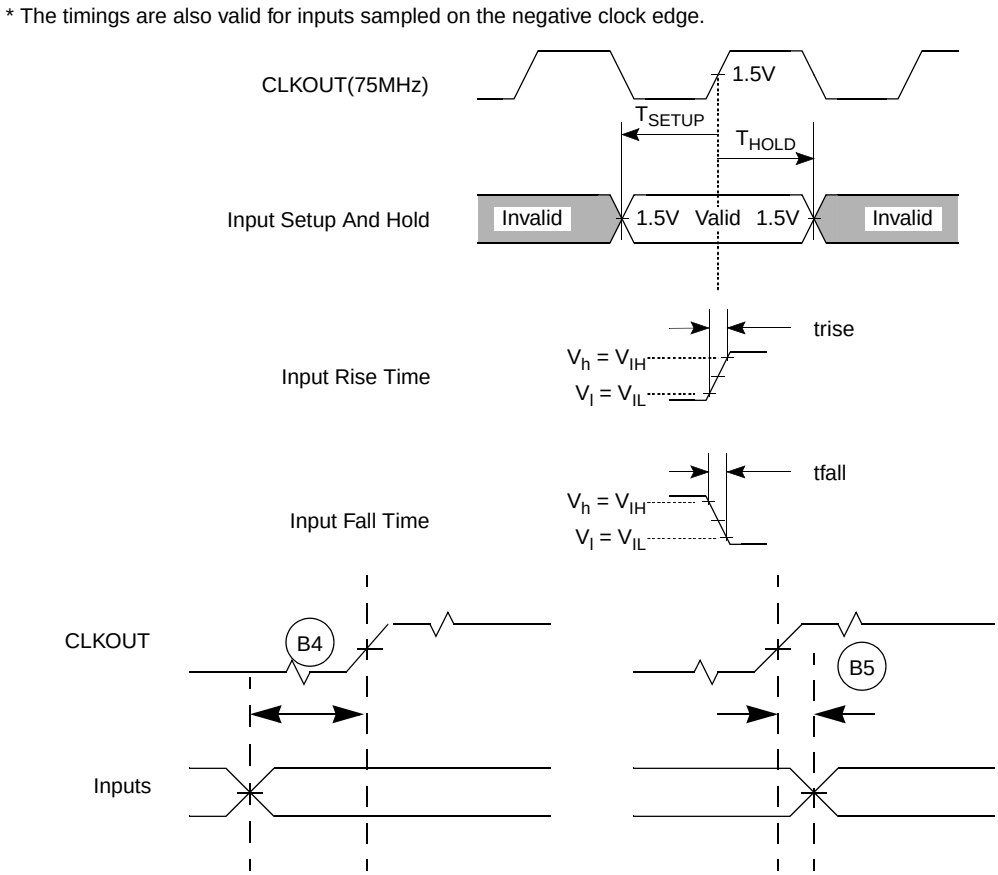


Figure 10. General Input Timing Requirements

7.6 Processor Bus Output Timing Specifications

Table 12 lists processor bus output timings.

Table 12. External Bus Output Timing Specifications

Name	Characteristic	Symbol	Min	Max	Unit
Control Outputs					
B6a	CLKOUT high to chip selects valid [1]	t_{CHCV}	—	$0.5t_{CYC}$ +5	ns
B6b	CLKOUT high to byte enables ($\overline{BS}$[3:0]) valid[2]	t_{CHBV}	—	$0.5t_{CYC}$ +5	ns
B6c	CLKOUT high to output enable ($\overline{OE}$) valid[3]	t_{CHOV}	—	$0.5t_{CYC}$ +5	ns
B7	CLKOUT high to control output ($\overline{BS}$[3:0], $\overline{OE}$) invalid	t_{CHCOI}	$0.5t_{CYC}$+1.5	—	ns
B7a	CLKOUT high to chip selects invalid	t_{CHCI}	$0.5t_{CYC}$+1.5	—	ns

Table 12. External Bus Output Timing Specifications (continued)

Name	Characteristic	Symbol	Min	Max	Unit
Address and Attribute Outputs					
B8	CLKOUT high to address (A[23:0]) and control ($\overline{TS}$, $\overline{TSIZ}$[1:0], $\overline{TIP}$, R/$\overline{W}$) valid	t_{CHAV}	—	9	ns
B9	CLKOUT high to address (A[23:0]) and control ($\overline{TS}$, $\overline{TSIZ}$[1:0], $\overline{TIP}$, R/$\overline{W}$) invalid	t_{CHAI}	1.5	—	ns
Data Outputs					
B11	CLKOUT high to data output (D[31:0]) valid	t_{CHDOV}	—	9	ns
B12	CLKOUT high to data output (D[31:0]) invalid	t_{CHDOI}	1.5	—	ns
B13	CLKOUT high to data output (D[31:0]) high impedance	t_{CHDOZ}	—	9	ns

1 $\overline{CS}$ transitions after the falling edge of CLKOUT.
2 $\overline{BS}$ transitions after the falling edge of CLKOUT.
3 $\overline{OE}$ transitions after the falling edge of CLKOUT.

Read/write bus timings listed in Table 12 are shown in Figure 11, Figure 12, and Figure 13.

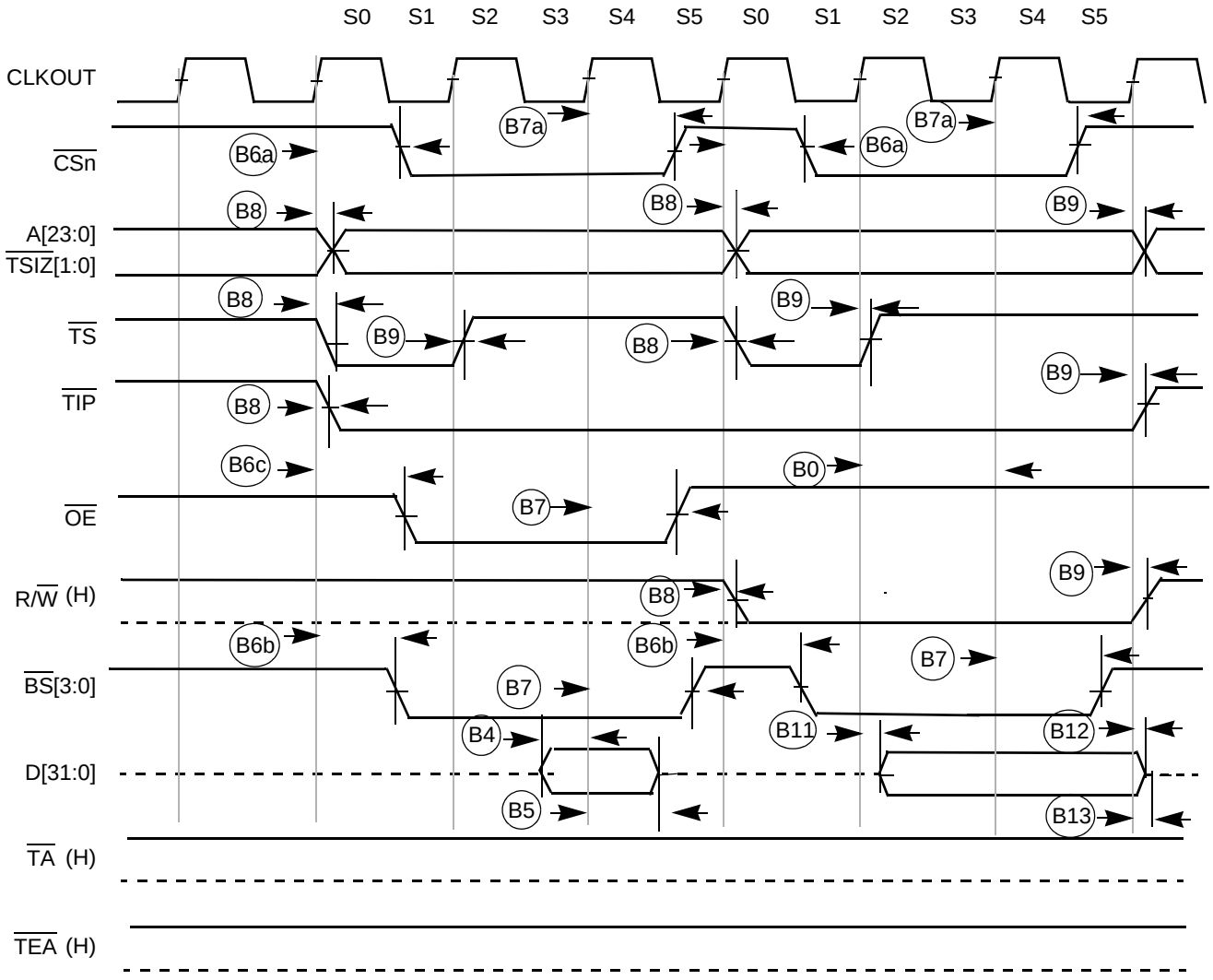


Figure 11. Read/Write (Internally Terminated) SRAM Bus Timing

7.9 I²C Input/Output Timing Specifications

Table 16 lists specifications for the I²C input timing parameters shown in Figure 18.

Table 16. I²C Input Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1	Start condition hold time	2	—	t_{cyc}
I2	Clock low period	8	—	t_{cyc}
I3	I2C_SCL/I2C_SDA rise time (V_{IL} = 0.5 V to V_{IH} = 2.4 V)	—	1	ms
I4	Data hold time	0	—	ns
I5	I2C_SCL/I2C_SDA fall time (V_{IH} = 2.4 V to V_{IL} = 0.5 V)	—	1	ms
I6	Clock high time	4	—	t_{cyc}
I7	Data setup time	0	—	ns
I8	Start condition setup time (for repeated start condition only)	2	—	t_{cyc}
I9	Stop condition setup time	2	—	t_{cyc}

Table 17 lists specifications for the I²C output timing parameters shown in Figure 18.

Table 17. I²C Output Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1[1]	Start condition hold time	6	—	t_{cyc}
I2 [1]	Clock low period	10	—	t_{cyc}
I3 [2]	I2C_SCL/I2C_SDA rise time (V_{IL} = 0.5 V to V_{IH} = 2.4 V)	—	—	µs
I4 [1]	Data hold time	7	—	t_{cyc}
I5 [3]	I2C_SCL/I2C_SDA fall time (V_{IH} = 2.4 V to V_{IL} = 0.5 V)	—	3	ns
I6 [1]	Clock high time	10	—	t_{cyc}
I7 [1]	Data setup time	2	—	t_{cyc}
I8 [1]	Start condition setup time (for repeated start condition only)	20	—	t_{cyc}
I9 [1]	Stop condition setup time	10	—	t_{cyc}

1 Note: Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 17. The I²C interface is designed to scale the actual data transition time to move it to the middle of the I2C_SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR; however, the numbers given in Table 17 are minimum values.

2 Because I2C_SCL and I2C_SDA are open-collector-type outputs, which the processor can only actively drive low, the time I2C_SCL or I2C_SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.

3 Specified at a nominal 50-pF load.

Figure 18 shows timing for the values in Table 16 and Table 17.

7.10.2 MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)

Table 19 lists MII transmit channel timings.

The transmitter functions correctly up to a ETXCLK maximum frequency of 25 MHz +1%. The processor clock frequency must exceed twice the ETXCLK frequency.

Table 19. MII Transmit Signal Timing

Num	Characteristic	Min	Max	Unit
M5	ETXCLK to ETXD[3:0], ETXEN, ETXER invalid	5	—	ns
M6	ETXCLK to ETXD[3:0], ETXEN, ETXER valid	—	25	ns
M7	ETXCLK pulse width high	35%	65%	ETXCLK period
M8	ETXCLK pulse width low	35%	65%	ETXCLK period

Figure 20 shows MII transmit signal timings listed in Table 19.

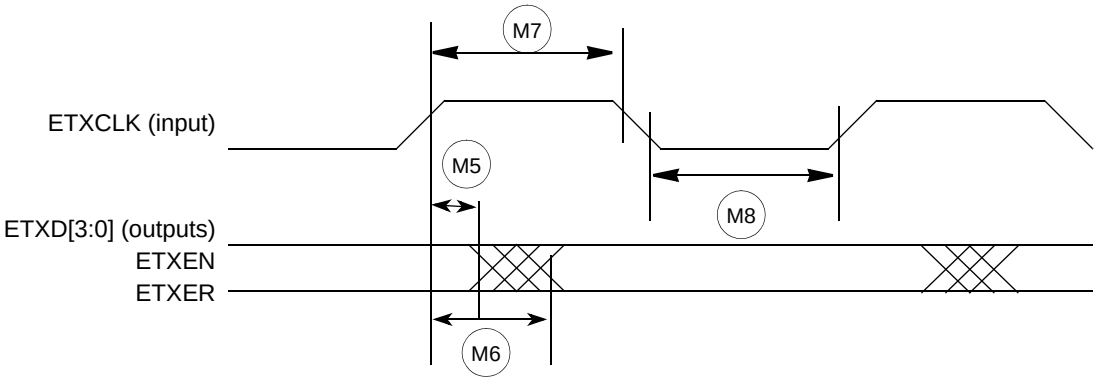


Figure 20. MII Transmit Signal Timing Diagram

7.10.3 MII Async Inputs Signal Timing (ECRS and ECOL)

Table 20 lists MII asynchronous inputs signal timing.

Table 20. MII Async Inputs Signal Timing

Num	Characteristic	Min	Max	Unit
M9	ECRS, ECOL minimum pulse width	1.5	—	ETXCLK period

Figure 21 shows MII asynchronous input timings listed in Table 20.

Figure 21. MII Async Inputs Timing Diagram

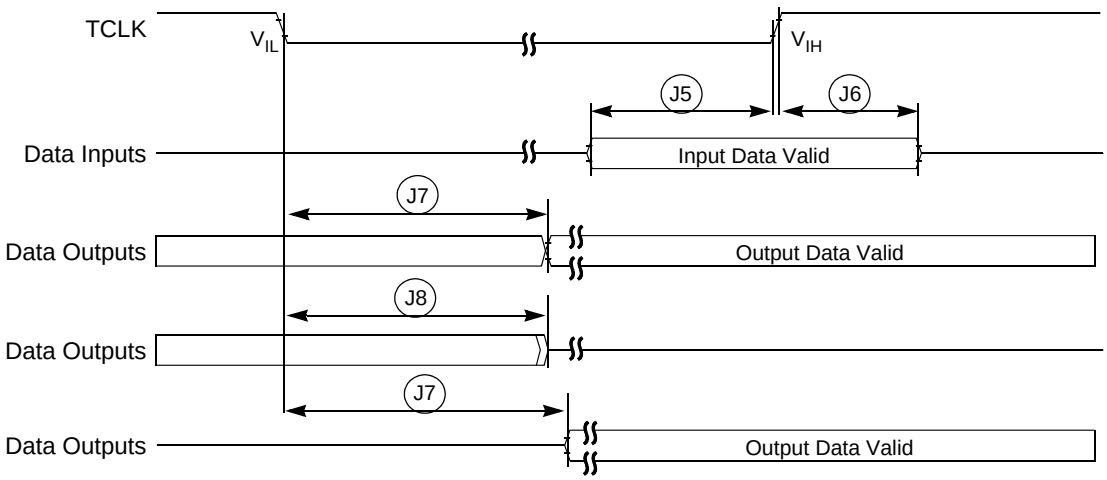


Figure 25. Boundary Scan (JTAG) Timing

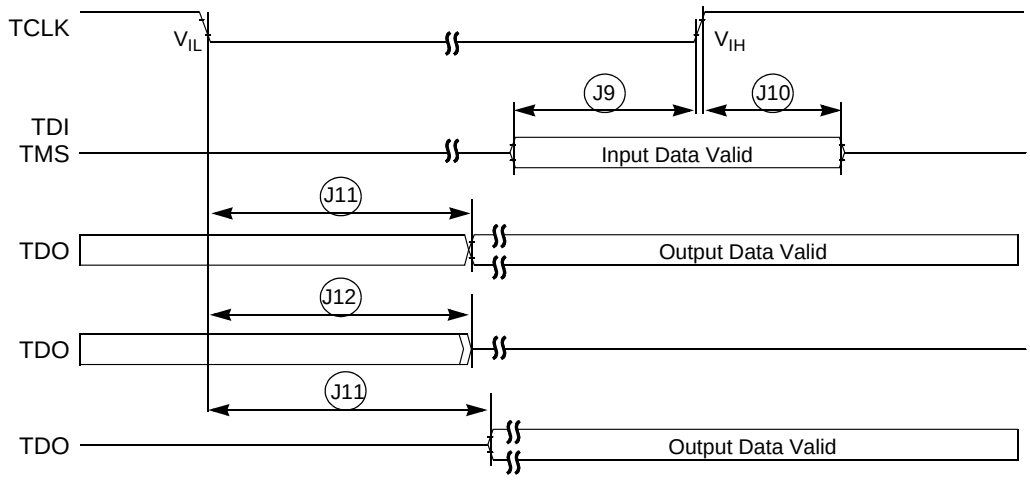


Figure 26. Test Access Port Timing

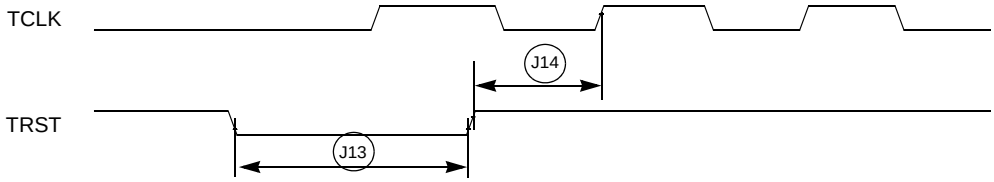


Figure 27. $\overline{\text{TRST}}$ Timing

7.14 Debug AC Timing Specifications

Table 25 lists specifications for the debug AC timing parameters shown in Figure 29.

Table 25. Debug AC Timing Specification

Num	Characteristic	150 MHz		Units
		Min	Max	
DE0	PSTCLK cycle time	—	0.5	t_{cyc}
DE1	PST valid to PSTCLK high	4	—	ns
DE2	PSTCLK high to PST invalid	1.5	—	ns
DE3	DSCLK cycle time	5	—	t_{cyc}
DE4	DSI valid to DSCLK high	1	—	t_{cyc}
DE5[1]	DSCLK high to DSO invalid	4	—	t_{cyc}
DE6	$\overline{\text{BKPT}}$ input data setup time to CLKOUT rise	4	—	ns
DE7	CLKOUT high to $\overline{\text{BKPT}}$ high Z	0	10	ns

1 DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 28 shows real-time trace timing for the values in Table 25.

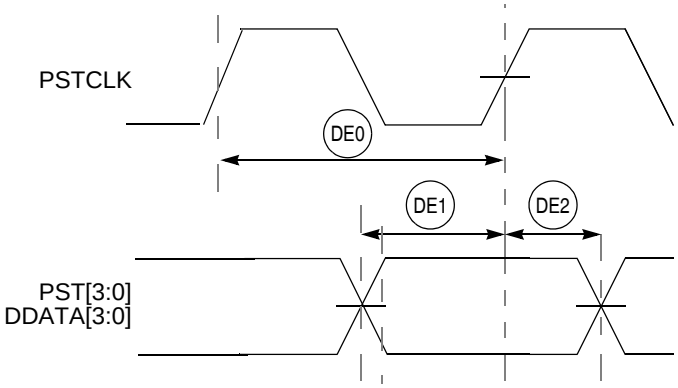


Figure 28. Real-Time Trace AC Timing

Figure 29 shows BDM serial port AC timing for the values in Table 25.

Table 26. MCF5235EC Revision History (continued)

Rev. No.	Substantive Change(s)
1.5	• Removed Overview, Features, Modes of Operation, and Address Multiplexing sections. This information can be found in the MCF5235 Reference Manual. • Removed list of documentation table in Section 8, "Documentation.". An up-to-date list is always available on our web site.
1.6	• Table 9: Changed core supply voltage (V_{DD}) from 1.35-1.65 to 1.4-1.6.
1.7	• Table 10: Changed max f_{ICO} frequency from "75 MHz" to "150 MHz".
1.8	• Added Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions." • Updated 196MAPBGA package dimensions, Figure 3.
2	• Table 2: Changed SD_CKE pin location from 139 to "—" for the 160QFP device. Changed QSPI_CS1 pin location from "—" to 139 for the 160QFP device. • Figure 8: Changed pin 139 label from "SD_CKE/QSPI_CS1" to "QSPI_CS1/SD_CKE". • Removed second sentence from Section 7.10.1, "MII Receive Signal Timing (ERXD[3:0], ERXDV, ERXER, and ERXCLK)," and Section 7.10.2, "MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)," regarding no minimum frequency requirement for TXCLK. • Removed third and fourth paragraphs from Section 7.10.2, "MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)," as this feature is not supported on this device.
3	• Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions" changed $PLLV_{DD}$ to V_{DDPLL} to match rest of document. • Section 5.2.1, "Supply Voltage Sequencing and Separation Cautions" Changed V_{DDPLL} voltage level from 1.5V to 3.3V throughout section. • Section 5.2.1.1, "Power Up Sequence" first bullet, changed "Use 1 µs" to "Use 1 ms". • Corrected position of spec D5 in Figure 14. • Table 14: Added $\overline{DACKn}$ and $\overline{DREQn}$ to footnote. • Table 9, added PLL supply voltage row
4	• Added part number MCF5235CVF150 in Table 6